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	Subclass	ISSUE CLASSIFICATION
	Class	

PATENT NUMBER

U.S. UTILITY Patent Application

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SCANNED	147(1)	O.A. Am

APPLICATION NO. 09/955310	CONT/PRIOR F	CLASS 324	SUBCLASS 765	ART UNIT 2829	EXAMINER Chan
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APPLICANTS

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TITLE

Apparatus and method for measuring electrical characteristics of a semiconductor element in a packaged semiconductor device

PTO-2040
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ISSUING CLASSIFICATION					
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CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
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